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Quarterly Reliability Monitoring Results

Quarters: 04/2018 to 03/2019

Based on structural similarity

Supplier		User Part Number						
Name of Laboratory		IP4786CZ32S						
		Part Description						
		NXP ICN8 Protection INDI						
		MCD package						
Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
# 2	PC Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	109	8690	0		
# 5	HTRB High Temperature Reverse Bias	MIL-STD-750-1 M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 hours	3	240	0		
# 7	TC Temperature Cycling	JESD22-A104 -55 °C to Tjmax, not to exceed 150°C	1000 cycles	42	3345	0		
# 8	AC Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	96 hours	26	2080	0		
# 9	H3TRB High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR > 80 % of rated reverse voltage	1000 hours	41	3265	0		
# 10	IOL Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj =	1000 hours	n.a.	n.a.	n.a.		
# 20	RSH Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
# 21	SD Solderability	J-STD-002 Test method B and D		27	270	0		

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

NXP ICN8 Protection INDI 240 0 17.69 5.65E+07	Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
	NXP ICN8	Protection INDI	240	0	17,69	5,65E+07

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